

## United States Patent and Trademark Office



UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
10/714,215	11/13/2003	Yuet-Ying Yu	END920030065US1 (IEN-10-5			
26681	7590 03/10/2005		EXAM	EXAMINER		
DRIGGS, LUCAS BRUBAKER & HOGG CO. L.P.A.			NGUYEN	NGUYEN, VINH P		
DEPT. IEN 8522 EAST A	VENUE	ART UNIT	PAPER NUMBER			
MENTOR, OH 44060			2829			
				DATE MAILED: 03/10/2005		

Please find below and/or attached an Office communication concerning this application or proceeding.

t								
Office Action Summary		Applicatio	Application No. Applicant(s)					
		10/714,21	5	YU ET AL.				
		Examiner		Art Unit				
		VINH P NO	GUYEN	2829				
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply								
THE - Exte after - If the - If NC - Failu Any	ORTENED STATUTORY PERIOD FOR MAILING DATE OF THIS COMMUNICATION of time may be available under the provisions of SIX (6) MONTHS from the mailing date of this communication of the period for reply specified above, the maximum statution to reply within the set or extended period for reply will reply received by the Office later than three months after the patent term adjustment. See 37 CFR 1.704(b).	ATION. 37 CFR 1.136(a). In no eve ication. days, a reply within the statu ory period will apply and will, by statute, cause the appli	nt, however, may a reply be tim tory minimum of thirty (30) days Lexpire SIX (6) MONTHS from cation to become ABANDONEI	nely filed s will be considered time the mailing date of this c D (35 U.S.C. § 133).				
Status								
1)⊠	Responsive to communication(s) filed	on 23 November 20	003.					
2a)∏	This action is <b>FINAL</b> . 2b)⊠ This action is non-final.							
3)								
, —	closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.							
Disposit	ion of Claims							
5)□ 6)⊠ 7)⊠								
Applicat	ion Papers							
10)⊠	The specification is objected to by the Interpretation of the drawing (s) filed on 13 November 2 Applicant may not request that any objection Replacement drawing sheet(s) including the oath or declaration is objected to be	2003 is/are: a)⊠ acon to the drawing(s) be correction is require	e held in abeyance. See ed if the drawing(s) is ob	e 37 CFR 1.85(a). jected to. See 37 C	FR 1.121(d).			
<b>Priority</b>	under 35 U.S.C. § 119							
<ul> <li>12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).</li> <li>a) All b) Some * c) None of:</li> <li>1. Certified copies of the priority documents have been received.</li> <li>2. Certified copies of the priority documents have been received in Application No.</li> <li>3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).</li> <li>* See the attached detailed Office action for a list of the certified copies not received.</li> </ul>								
2) Notice 3) Infor	nt(s)  ce of References Cited (PTO-892)  ce of Draftsperson's Patent Drawing Review (PTO- mation Disclosure Statement(s) (PTO-1449 or P <sup>-</sup> er No(s)/Mail Date <u>1103</u> .		4) Interview Summary Paper No(s)/Mail Di 5) Notice of Informal F 6) Other:	ate	O-152)			

Application/Control Number: 10/714,215 Page 2

Art Unit: 2829

1. The title of the invention is not descriptive. A new title is required that is clearly indicative of the invention to which the claims are directed.

- 2. The abstract of the disclosure is objected to because legal phraseology such as "means" is used. Correction is required. See MPEP § 608.01(b).
- 3. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 4. Claims 1-2 and 10-11 are rejected under 35 U.S.C. 102(b) as being anticipated by Matrone (Pat # 4,352,061).

As to claims 1 and 10, Matrone discloses a test fixture as shown in figures 2- 3 having a multi-probe tester (14), with a plurality of test probes (30,47) arranged in a distribution pitch, an electrical circuit testing apparatus (13), a module (18) having a top surface comprsing a first electrical device with a first plurality of contact pads (19) arrayed in the distribution ptch on a first device tip surface and means for masking (16) for masking at least one first test probe when the plurality of test probes are brought into contact with the first device tip surface to form a first electrical engagement. It is noted that the testing apparatus provides a circuit test run.

As to claims 2 and 11, it appears that the mask membrane (16) defining a first aperture (34) and disposed between the first device tip surface and the plurality of probes (30,47) wherein the tisrt at least one test probe is aligned to contact the mask member (16) an a first remainder of the test probes (30,47) is aligned within the first aperture (34) therby passing through the mask member (16). It is noted that the mask member prevents the first at least one test probe from making contact with the module top surface.

5. Claims 19-20 are rejected under 35 U.S.C. 102(b) as being anticipated by Burr et al (Pat # 4,565,966).

As to claim 19, Burr et al disclose an apparatus for testing of electrical interconnection networks as shown in figure 1 having a control computer (40) for controlling a plurality of test probes (20,22) when a program inside the control computer is executed, the computer is able to select and disregard at least one test probe input from a test routine executed on the probes (20,22). It appears that the computer (40) inherently includes a memory (computer usable medium) for storing a computer readable program for controlling the test probes.

As to claim 20, it appears that the computer of Burr et al also cause to select and disregard a second probe (20) or the first probe (22).

6. Claims 3-9 and 12-18 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Art Unit: 2829

The prior art does not disclose multi probe tester having a tool application program configured to control the test probes and means for masking the test probes is at least one software loaded into the tool application program to cause an input from the first test probe to be disregarded during a test routine, in combination with other claimed elements.

7. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Vaucher (pat # 5,216,358) disclose device for testing a printed circuit board.

Fjelstad (pat # 6,211,690) disclose an apparatus for electrically testing bare printed circuits.

Fohlich (Pat # 4,471,298) disclose an apparatus for automatically electrically testing printed circuit boards.

Look et al (Pat # 5,150,042) disclose on-wafer hall effect measurement system.

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to VINH P NGUYEN whose telephone number is (571)-272-1964. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent

Application Information Retrieval (PAIR) system. Status information for published applications

may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

VINH P. NOUYEN PRIMARY EXAMINER

**ART UNIT 2829** 

03/03/05